PTO/SB/08A (10-01)
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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet

Complete if Known					
Application No.	10/782,267				
Filing Date	February 18, 2004				
First Named Inventor	Steven W. Meeks				
Art Unit	2877				
Examiner Name	Not Yet Known				
Attorney Docket Number	20830-08855				

U.S. PATENT DOCUMENTS								
		Document No.						
Examiner Initials*	Cite No.1	Number – Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document				
TN	A1	3,885,875	05/27/1975	Rosenfeld et al.				
1	A2	4,332,477	06/01/1982	Sato				
	A3	4,585,348	04/29/1986	Chastang et al.				
	A4	4,668,860	05/26/1987	Anthon				
	A5	4,870,631	09/26/1989	Stoddard				
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	A10	5,196,906	03/23/1993	Stover et al.				
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	A12	5,293,216	03/08/1994	Moslehi				
	A13	5,313,542	05/17/1994	Castonguay				
	A14	5,406,082	04/11/1995	Pearson et al.				
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	A24	5,748,305	05/05/1998	Shimono et al.				
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1,	A29	5,880,838	03/09/1999	Marx et al.				
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Examiner Signature	TV	Date Considered	10/28/04
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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INEC	DMATIO	N DISC	LOSURE	Application No.	10/782,267	
•				Filing Date	February 18, 2004	
STATEMENT BY APPLICANT				First Named Inventor	Steven W. Meeks	
				Art Unit	2877	
				Examiner Name	Not Yet Known	
Sheet	. 2	of	4	Attorney Docket Number	20830-08855	

	U.S. PATENT DOCUMENTS							
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Examiner Initials*	Cite No.	Number - Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document				
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	A32	5,978,091	11/02/1999	Jann et al.				
	A33	5,985,680	11/16/1999	Singhal et al.				
	A34	5,986,761	11/16/1999	Crawforth et al.				
	A35	5,986,763	11/16/1999	Inoue				
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	A38	6,088,092	07/11/2000	Chen et al.				
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Examiner Signature	TV	Date Considered	10/28/04
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	Substitute for	form 1449/	VPTO		Complete if Known	
INE		א חופי	CLOSURE	Application No.	10/782,267	
•			PLICANT	Filing Date	February 18, 2004	
317	AI EIVIEN I	DT AF	PLICANI	First Named Inventor	Steven W. Meeks	
				Art Unit	2877	•
				Examiner Name	Not Yet Known	
Sheet	. 3	of	4	Attorney Docket Number	20830-08855	

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		Document No.			<del></del>			
Examiner Initials*	Cite No.1	Number – Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document				
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		Foreign Patent Document		. ,				
Examiner Initials*	Cite No.1	Country Code <sup>3</sup> – Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD- YYYY	Name of Patentee or Applicant of Cited Document	T <sup>6</sup>			
TN	B1	WO 98/52019	11/19/1998	Technische Universiteit Delft				
TN	B2	JP 3-221804	09/30/1991	NEC Corp				

Examiner Signature	TN	Date Considered	10/28/04	
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	Substitute for fo	rm 1449	A/PTO .	Complete if Known		
INEC		חופו	CLOSURE	Application No.	10/782,267	
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•				Art Unit	2877	
				Examiner Name	Not Yet Known	
Sheet	· 4	of	4	Attorney Docket Number	20830-08855	

		OTHER REFERENCES - NON-PATENT LITERATURE DOCUMENTS			
Examiner fhitials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	<b>T</b> <sup>6</sup>		
Ta	W.C. Leung, W. Crooks, H. Rosen and T. Strand, An Optical Method Using a Laser and an Integrating Sphere Combination for Characterizing the Thickness Profile of Magnetic Media, Sept. 1989, IEEE Transaction on Magnetics, Vol. 25, No. 5. Pages 3659-3661.				
	C2	Steven W. Meeks, Walter E. Weresin, and Hal J. Rosen, <i>Optical Surface Analysis of the Head-Disk-Interface of Thin Film Disks</i> , January 1995, Transactions of the ASME, Journal of Tribology, Vol. 117, pages 112-118.			
	C3	Steven Meeks, Maxtor and Rusmin Kudinar, <i>The Next Battleground: Head-Disk Interface</i> , March 1998, Data Storage, Test & Measurement, pages 29-30, 34 and 38.			
	C4	Laser Scanning Surface Profilometer, [online], August 1970, [retrieved January 29, 2001], Pages 789-790, Retrieved from the Internet: <url: http:="" tdb?&order="7OC101758.&lt;/td" tdbs="" www.delphion.com=""><td></td></url:>			
7~	C5	Meeks, Steven W.: "A Combined Ellipsometer, Reflectometer, Scatterometer and Kerr Effect Microscope for Thin Film Disk Characterization," Machine Vision Applications in Industrial Inspection VIII, Proceedings of SPIE, vol. 3966, 2000, pages 385-391, XP001085220.			

Examiner Signature	TV	Date Considered	10/28/04
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				Filing Date	February 18, 2004	
STATEMENT BY APPLICANT			PLICANI	First Named Inventor	Steven W. Meeks	
				Art Unit	2877	
				Examiner Name	Tu T. Nguyen	
Sheet	1	of	1	Attorney Docket Number	20830-08855	

U.S. PATENT DOCUMENTS					
		Document No.			
Examiner Initials*	Cite No.1	Number – Kind Code <sup>2</sup> (if known)	Date MM-YYYY	Name of Patentee or Applicant of Cited Document	
TW	A1	US-6,639,662	10-2003	Vaez-Iravani et al.	
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			FOREIGN PATENT D	OCUMENTS	
	T	Foreign Patent Document			
Examiner Initials*	Cite No.1	Country Code <sup>3</sup> – Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Τ <sup>6</sup>
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		OTHER REFERENCES - NON-PATENT LITERATURE DOCUMENTS					
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